Technology Arts Sciences TH Köln

Course TO - Technical optics

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<u>General information</u>

Long name	Technical optics
Approving CModule	<u>TO BAET, TO BAOPT</u>
Responsible	Prof. Dr. Stefan Altmeyer Professor Fakultät IME
Level	Bachelor
Semester in the year	summer semester
Duration	Semester
Hours in self-study	78
ECTS	5
Professors	Prof. Dr. Stefan Altmeyer Professor Fakultät IME
Requirements	mathematics: differntial calculus integral calculus physics / optics: basics of geometrical optics basics of wave optics
Language	German
Separate final exam	Yes

Final exam

Standard for this lecture is a written exam.

If the number of participants is not too high, an oral examination is preferred over written exams.

Lowest competence level checked is knowledge. Questions could address the sign convention, the structure of the imaging equation in dependence of light direction, the definition of the principal ray or the labelling of optical components conforming to industry standards.

The next competence level is related to skills. Examination could be done by the task to draw the optical path of rays of optical systems whereas the qualitative correct position of functional planes is important. Furthermore calculations can be performed, e.g. the resolution of optical systems, the image shift in systems with regions of differing refractive indices, of the overall focal length of a compund system.

The highest competence level adressed is methodical expertise. It can be checked by a real world task: E.g. the design of a microscope with an own light source where some application paramters to achieve are given or some off the shelf components are given. In a guided discussion or guided calculation it can be found out easily, if the underlying principles are understood and can be applied proactively, if intellectual transfer is made and if there is sufficient overview.

Minimum standard

Correct answer of at least 50 % of the questions

Exam Type

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<u>Lecture</u>

Learning goals

Knowledge

maginification reproduction scale angular magnification magnifier magnification axial magnification intendes shift of principal planes telephoto lens reverse telephot lens, laser material processing

multi lens systems analytical calculation of a doublet focal group of a camera acessory lenses for macro photos calculation of multi lens systems by repeated doublet calculation approach of lens grouping in objectives

image shift

under water photography special microscopy objectives foruse with cover glass optical aberrations of plane-parallel glass sheets

Principle of Fermat derivation of the law of refraction wave-optical explaination of the properties of a lens derivation of the sine condition

Aperture and F# number aperture of a glass fiber of an optical imaging system F# number written F# number effective F# number relation of aperture and (effective) F# number object- and image-related apertures and F# numbers image brightness and exposure time

diffraction at a circular apertur mathematical description criteria for resolution Rayleigh criterium Sparrow criteriium size of the Airy disc smallest resolvable distance in the object and in the image in terms of the apertures and F# numbers beneficial and empty magnification technical examples: optical lithography, microscope, optical pickup for CD/DVD/blu-ray

lenses

imaging lens: glass and plastics field lens: suitability of Fresnel lenses, requirements regarding dust

hard apertures and images of them aperture stop and field stop pupils and portholes principal rays complementary roles of aperture- and field-stops in imaging- and lighting-raypaths principles of construction for optical devices with own light sources. Examples: overheadprojector, beamer, microscope Microscopes simple and joint with and without field lens reflection and transmission Köhler illumination interwoven light ptahs of imaging and illumination path

If there is enough time in the semester:

Abbe's theory of imaging Decomposition of any object into gratings, Fourier decomposition Diffraction orders: number of and phas-relationship limiting resolution contrast off-axis illumination how to build resolution enhancement decrease of contrast principles of construction of a lithography machine

Skills

Analyse, calculate and design multi lens optical systems paraxially

Shift the principal planes to intended locations in optical systems.

Convert Apertured and F# numbers on the object- and image side.

Calculate imaging resolution of optical systems on the object- and image side.

Calculate the image shift.

Calculate the resolution loss due to angular dependent image shift of high aperture systems.

Design raypaths of optical systems with integrated illumination

Transfer the principles of construction of different microscope types to other optical devices.

Calculate the contrast of optical on- and off-axis systems

Expenditure classroom teaching

Туре	Attendance (h/Wk.)
Lecture	2
Tutorial (voluntary)	0

<u>Practical training</u>

Learning goals

Skills

- Build and align a Gallilei and a Kepler telescope

- Determine the focal lenght of an objective with the method of Abbe, Bessel or different
- Determine the principal planes with the method of Abbe of by extrapolation of the reproduction scale
- Determine the resolution of a microscope with Köhler illumination
- Determine image brightness in a microscope in dependence of reproduction scale and aperture.

- Watch and compare the object and the diffraction image in the Fourier plane in a diffraction apparatus. Perform intended image manipulations by modifications in the Fourier plane. Achieve e.g. a spatial frequency doubling.

write scientific report
describe the task
descirbe the idea of the solution
explain the experimental setup
explain the data processing
make error analysis
present the results and make a critical discussion

Expenditure classroom teaching

Туре	Attendance (h/Wk.)
Practical training	2
Tutorial (voluntary)	0

Separate exam

Exam Type

working on projects assignment with your team e.g. in a lab)

Details

1) Written examination questions related to the experiment have to be prepared at home and shown at the beginning of the laboratory.

2) The underlying ideas of the experiment have to be explained at the beginning of the laboratory.

3) Make the experiment alone (preferred) or in a team of two.

- Build up and adjust your own setup
- Acquire / measure date with this setup

4) Write a documentation on the experiment. It will be checked wih regard to

- completness
- scientific and precise language
- correctness

- understanding of the interrellations and interpretation of the results

Minimum standard

All written tasks must have been delt with.

The basic ideas of the experiment must have been understood.

All experiments must have been performed.

The reports must be free of systematical errors.

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